

●General Description

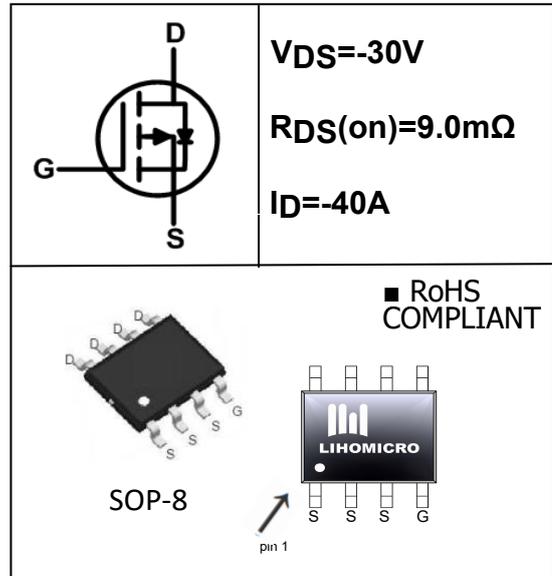
The LH40P03 uses trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. This device is suitable for high current load applications.

●Features

- Advance high cell density trench technology
- Low $R_{DS(ON)}$ to minimize conductive loss
- Low Gate Charge for fast switching

●Application

- Lighting
- Power Supplies


●Ordering Information:

Part Number	LH40P03
Package	SOP-8
Basic Ordering Unit (pcs)	4000
Normal Package Material Ordering Code	LH40P03S-SOP8-TAP
Halogen Free Ordering Code	LH40P03S-SOP8-TAP-HF

●Absolute Maximum Ratings (TC =25°C)

PARAMETER	SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	-30	V
Gate-Source Voltage	V_{GS}	±20	V
Continuous Drain Current , $T_C = 25^\circ C$	I_D	-40	A
Pulsed drain current ($T_C = 25^\circ C$, tp limited by T_{jmax}) ¹	I_{DM}	-80	A
Single Pulse Avalanche Energy ²	E_{AS}	96	mJ
Power Dissipation ³	$P_D(T_A=25^\circ C)$	3	W
	$P_D(T_A=70^\circ C)$	2	
Operating Temperature	T_J	-55~+150	°C
Storage Temperature	T_{STG}	-55~+150	°C

●Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	-30	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	-1.0	-1.5	-3.0	V
Drain-source On Resistance ¹	$R_{DS(ON)}$	$V_{GS} = -10V, I_D = -20A$	7.0	8.0	9.0	mΩ
		$V_{GS} = -4.5V, I_D = -15A$	--	10	13	
Drain-Source Leakage Current	I_{DSS}	$V_{DS} = -30V, V_{GS} = 0V, T_J = 25^\circ C$	--	--	-1	μA
Gate-Source Leakage Current	I_{GSS}	$V_{GS} = \pm 20, V_{DS} = 0V$	--	--	±100	nA
Forward Transconductance	G_{FS}	$V_{DS} = -5V, I_D = -20A$	--	5	--	S
Input Capacitance	C_{iss}	$V_{GS} = 0V,$ $V_{DS} = -15V,$ $f = 1.0MHz$	--	2379	--	pF
Output Capacitance	C_{oss}		--	409	--	
Reverse transfer Capacitance	C_{rss}		--	388	--	
Turn-On Delay Time	$T_{d(on)}$	$V_{DS} = -15V,$ $V_{GS} = -10V,$ $R_G = 1\Omega,$ $I_D = -15A$	--	26	--	nS
Turn-Off Delay Time	$T_{d(off)}$		--	136.5	--	
Turn-On Rise Time	T_r		--	65.7	--	
Turn-Off Fall Time	T_f		--	86.2	--	
Total Gate Charge	Q_g	$I_D = -20A,$ $V_{DS} = -15V,$ $V_{GS} = -4.5V$	--	31	---	nC
Gate-to-Source Charge	Q_{gs}		--	10.1	--	
Gate-to-Drain Charge	Q_{gd}		--	17.4	---	
Continuous Diode Forward Current ¹	I_S	$V_{GS} = V_{DS} = 0V,$ Force Current	--	--	-40	A
Pulsed Diode Forward Current	I_{SM}	--	--	--	-80	A
Diode Forward Voltage	V_{SD}	$T_J = 25^\circ C, I_S = -20A,$ $V_{GS} = 0V$	--	--	-1.0	V

●Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R_{thJC}	2.1	°C/W
Thermal Resistance Junction-ambient ⁴ ($t \leq 1s$)	R_{thJA}	50	°C/W

Notes:

- 1.Pulse Test : Pulse width $\leq 300 \mu s$, Duty cycle $\leq 2\%$;
- 2.The EAS data shows Max. rating.The Test condition is $L=0.5mH, I_D=16A, V_{DD}=-15V$;
- 3.The Power Dissipation is limited by $150^\circ C$ junction temperature;
- 4.Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.

• Typical Characteristics

Fig.1 Power Dissipation Derating Curve

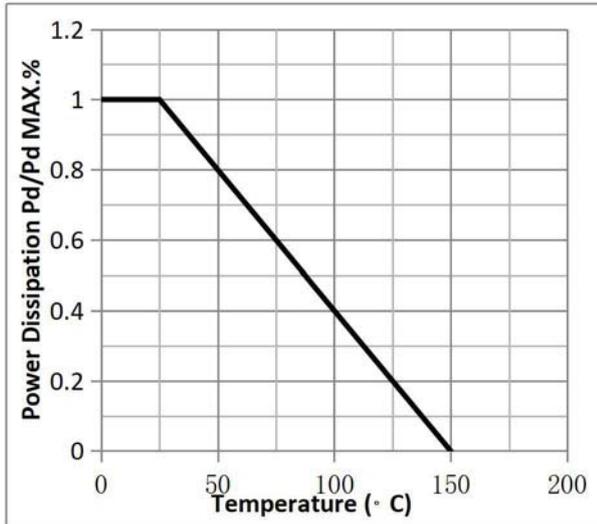


Fig.2 Typical output Characteristics

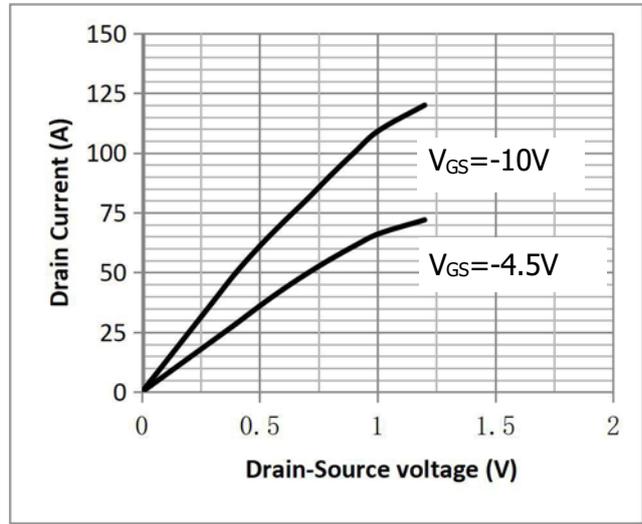


Fig.3 Threshold Voltage V.S Junction Temperature

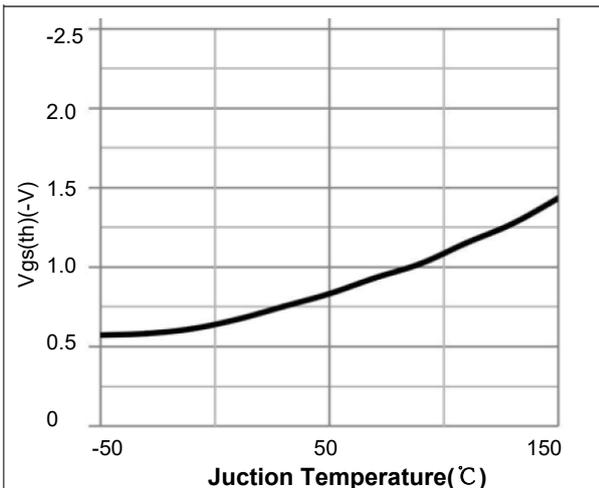


Fig.4 Resistance V.S Drain Current

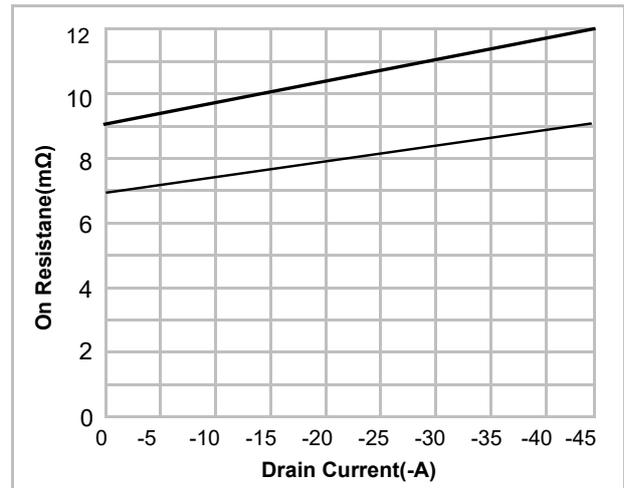


Fig.5 On-Resistance VS Gate Source Voltage

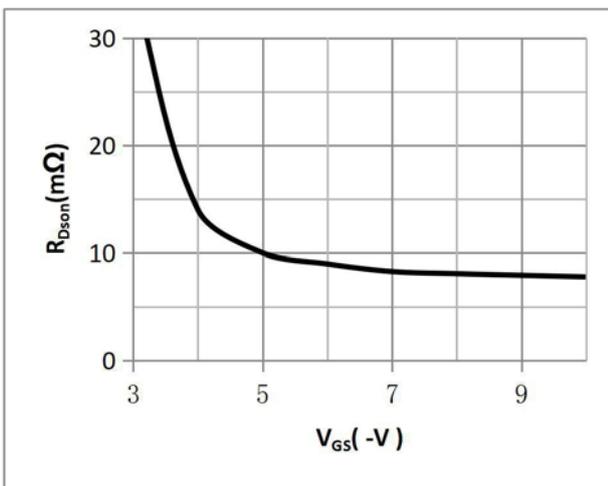
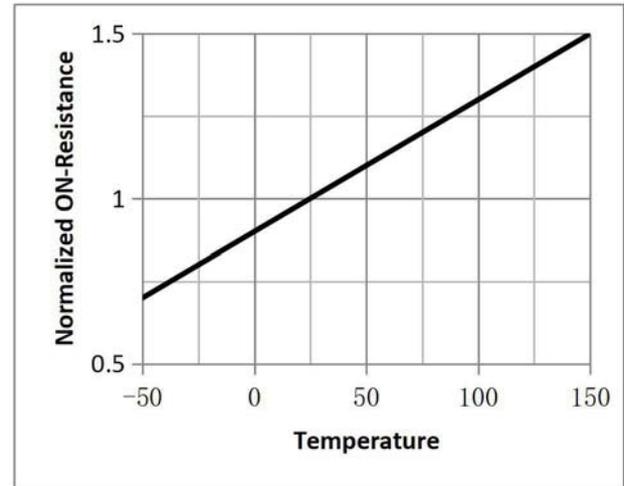


Fig.6 On-Resistance V.S Junction Temperature



•Test Circuits & Waveforms

Fig.7 Switching Time Measurement Circuit

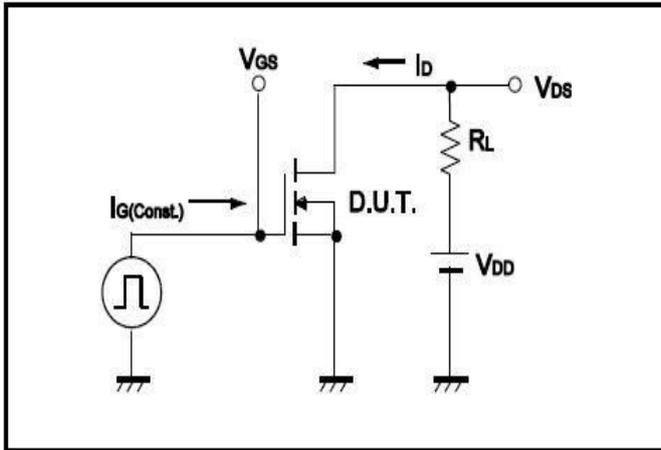


Fig.8 Gate Charge Waveform

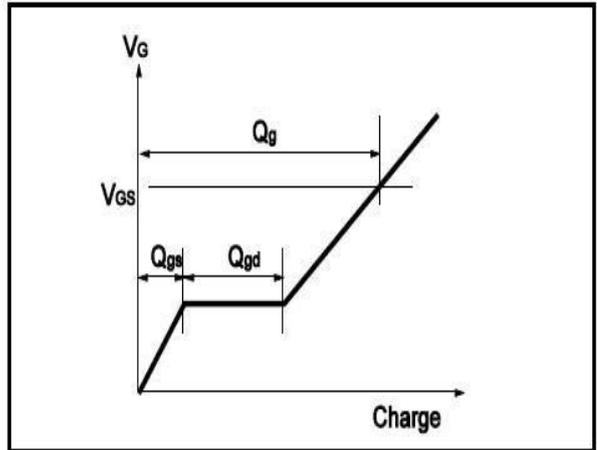


Fig.9 Switching Time Measurement Circuit

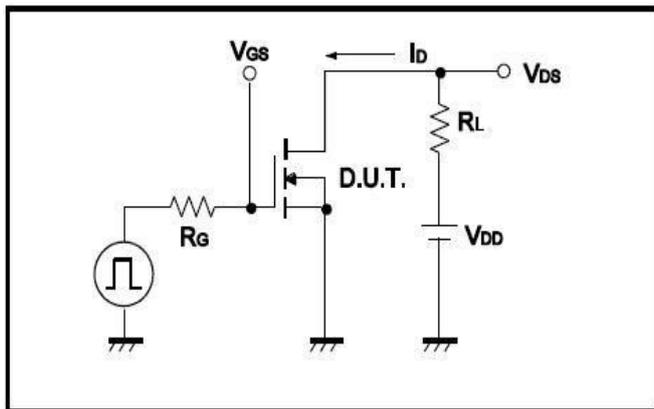


Fig.10 Gate Charge Waveform

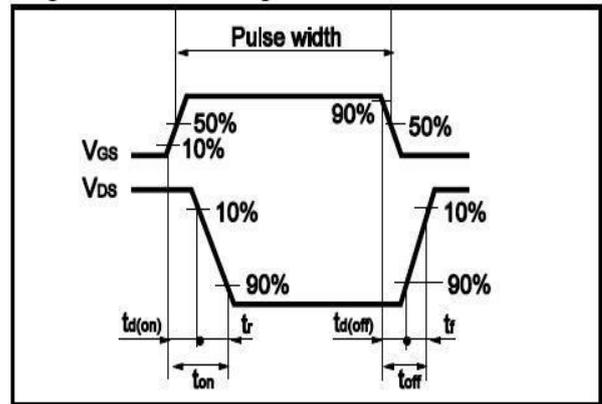


Fig.11 Avalanche Measurement Circuit

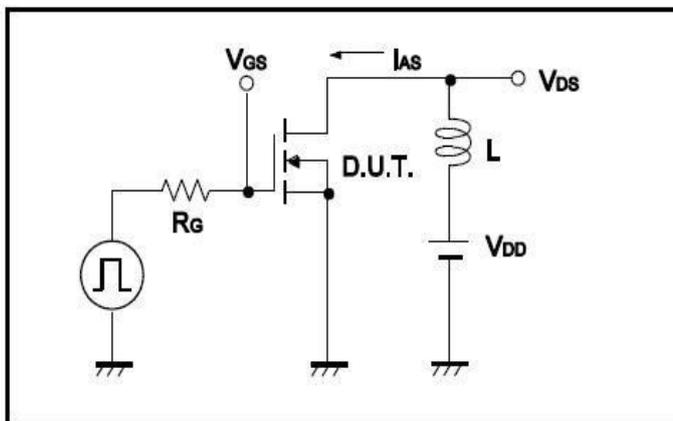
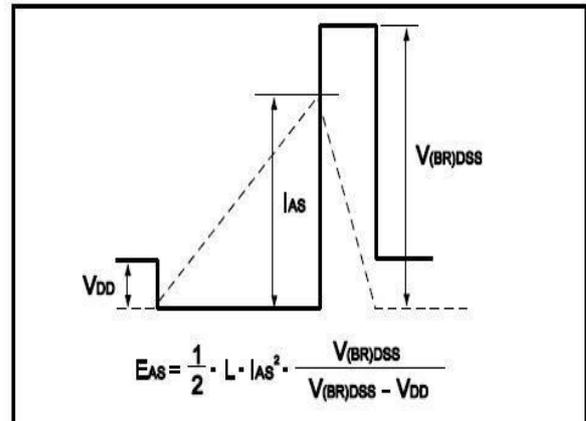


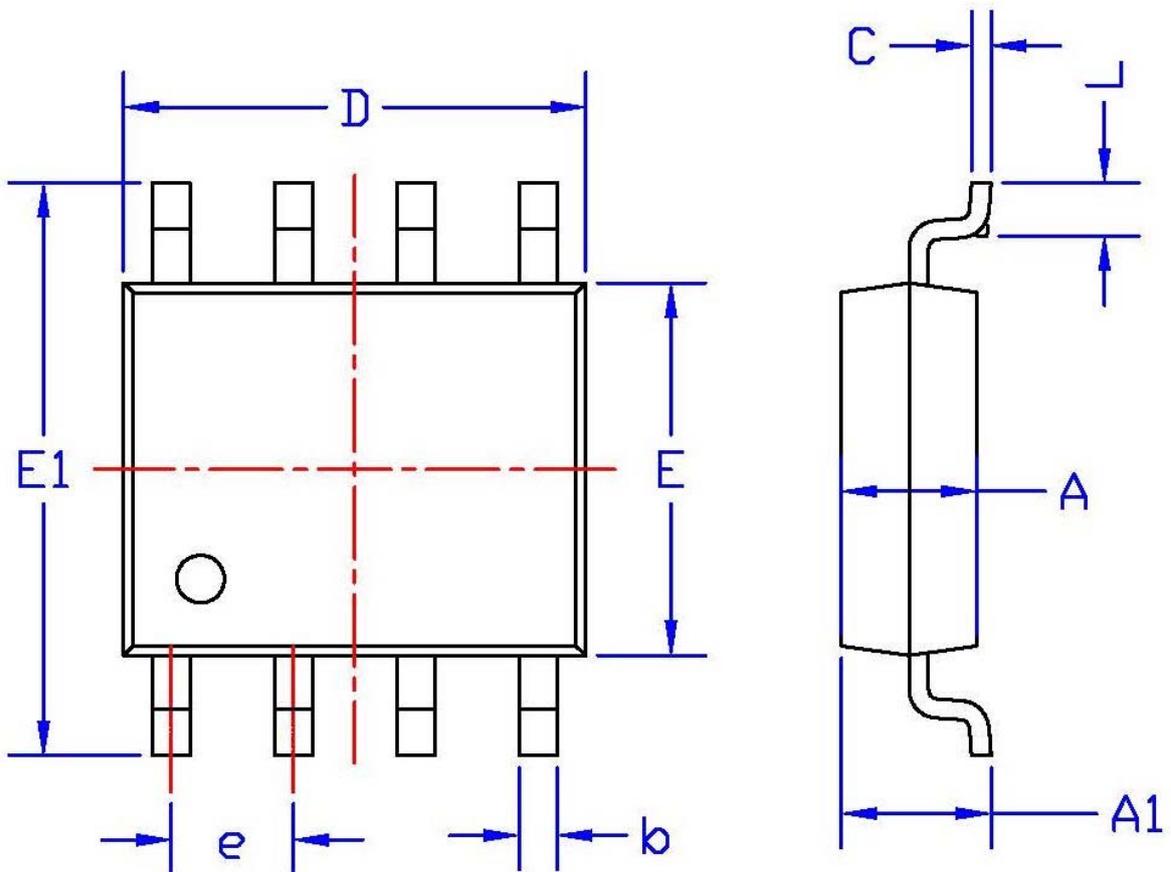
Fig.12 Avalanche Waveform



•Dimensions (SOP-8)

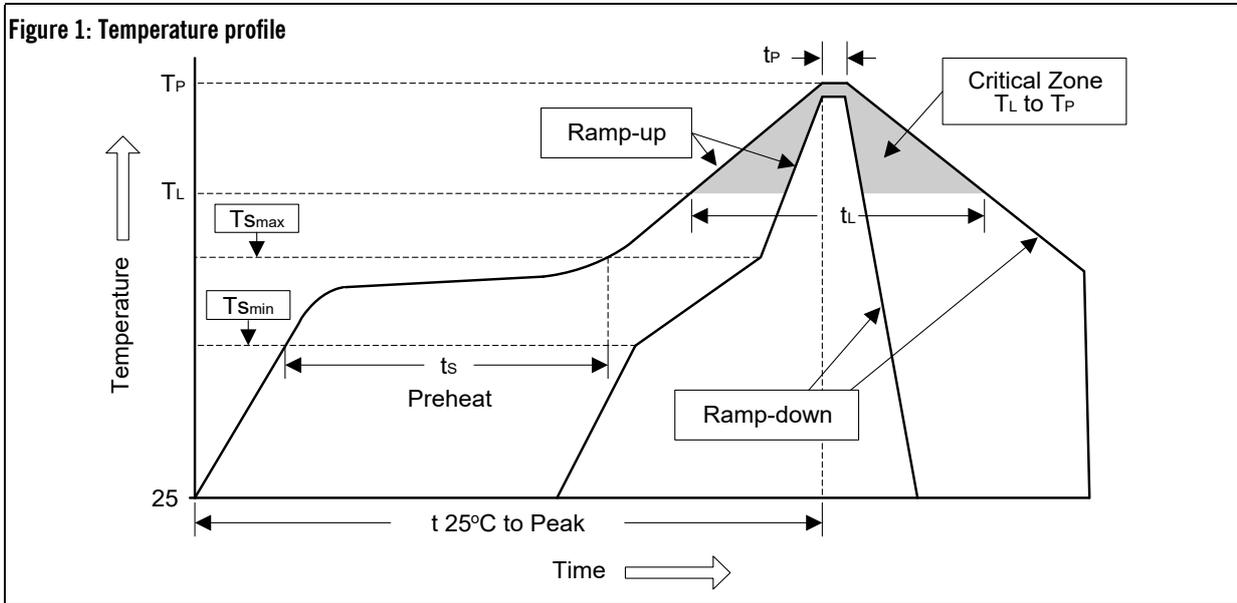
UNIT:mm

SYMBOL	min	max	SYMBOL	min	max
A	1.30	1.60	e	1.27BSC	
A1	1.35	1.85	L	0.40	1.30
b	0.30	0.60			
C	0.15	0.35			
D	4.60	5.20			
E	3.70	4.10			
E1	5.70	6.30			



• Soldering Methods for Silicongear's Products

1. Storage environment: Temperature=10°C to 35°C Humidity=65%±15%
2. Reflow soldering of surface-mount devices



Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate (T_L to T_P)	<3°C/sec	<3°C/sec
Preheat		
- Temperature Min (T_{smin})	100°C	150°C
- Temperature Max (T_{smax})	150°C	200°C
- Time (min to max) (t_s)	60 to 120 sec	60 to 180 sec
T_{smax} to T_L		
- Ramp-up Rate	<3°C/sec	<3°C/sec
Time maintained above:		
- Temperature (T_L)	183°C	217°C
- Time (t_L)	60 to 150 sec	60 to 150 sec
Peak Temperature (T_P)	240°C +0/-5°C	260°C +0/-5°C
Time within 5°C of actual Peak Temperature (t_p)	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25°C to Peak Temperature	<6 minutes	<8 minutes

3. Flow (wave) soldering (solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices.	245°C ±5°C	5sec ±1sec
Pb-Free devices.	260°C +0/-5°C	5sec ±1sec